Design for Testability Based on Single-Port-Change Delay Testing for Data Paths

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Abstract

This paper introduces a new concept of hierarchical testability called Single-Port-Change (SPC) two-pattern testability. We propose a non-scan design-for-testability (DFT) method which makes each path that needs to be tested in a data path SPC two-pattern testable. An SPC two-pattern test guarantees robust (resp. non-robust) test if the path is robust (resp. non-robust) testable. Since it is easy to find justification paths for SPC two-pattern tests at register-transfer level, the proposed DFT method can reduce hardware overhead compared to that of our previous DFT method for arbitrary two-pattern tests. Furthermore, we propose a method to reduce test generation effort by removing a subset of sequentially untestable paths from targets of test generation. Experimental results show that the proposed method can reduce hardware overhead without losing the quality of test.

1. Introduction

The speed of VLSI circuits has accelerated in recent years. High speed VLSI circuits need delay fault testing in order to guarantee the timing correctness of the circuits. There are several delay fault models: path delay fault model, transition fault model, segment fault model, and so on. Among these, path delay fault is more general and models defects as cumulative propagation delays along circuit paths that exceed an upper limit[1]. To detect a path delay fault in a circuit, it is necessary to apply a two-pattern test to the starting points of a target and other related paths. However, it takes a lot of time for general VLSI circuits to generate test sequence for justification of two-pattern tests. Straightforward solutions are scan-based approaches[2, 3, 4]. However, these techniques have the following disadvantages: (i) under-testing problem arises or (ii) complex test generation is needed and/or (iii) area overhead is high. Moreover, test application time is long because of scan-shift operation. To avoid the disadvantages, non-scan design-for-testability (DFT) approaches at register-transfer level (RTL) based on hierarchical test generation have been proposed[5, 6]. The advantage of this approach is that the number of primitive elements at RTL is much small compared to that at gate level. Hierarchical test generation consists of two processes, (i) generating test patterns for combinational blocks at gate-level, (ii) justifying the patterns from primary inputs (PIs) to appropriate registers and propagating the responses to primary outputs (POs) at RTL. Our previous work[6] defined hierarchical two-pattern testable (HTPT) data path, in which any two-pattern tests can be applied to each combinational block from PIs and the responses can be observed at POs. They presented a DFT method at RTL to augment a given data path to HTPT data path, which requires lower area overhead and test application time than enhanced scan approach does. However there is room for further improvement in area overhead. Furthermore, there is possibility of over-testing. Over-testing means that untestable faults before DFT can be tested after DFT. As a result, it leads to lower the process yield and judge good circuits as defective ones. Therefore, it is important to reduce area overhead and reduce over-testing.

Path delay faults in a combinational circuit are generally classified into four classes: robust testable, non-robust testable, functional sensitizable (FS) and functional unsensitizable path delay faults[1]. In [8], robust and non-robust testable path delay faults are classified as the same group called singly-testable (ST). In [7, 8], a path delay fault is robust (resp. non-robust) testable if and only if there exists a Single-Input-Change (SIC) robust (resp. non-robust) test for the fault. In this paper, we propose a new concept of testability at RTL called Single-Port-Change (SPC) two-pattern testability based on the concept of SIC at gate-level. A port means an input and an output of primitive elements (e.g. an operational module and a register) at RTL, and it has bit width. At RTL, a number of combinational 1-bit paths between two ports are regarded as a bundled path. We employ the notion of RTL paths[6]. An RTL path is a path passing through only combinational logic, which starts at a PI or a register and ends at a register or a PO. $PI1$-$m1$-$m2$-$Add1$-$R5$ and $R2$-$Add2$-$R4$ are two examples of RTL paths in figure 4. A proposed DFT method guarantees SPC two-pattern testability to every combinational block at RTL based on hierarchical test generation, which can reduce area overhead compared to the previous DFT method for HTPT. SPC two-pattern tests can guarantee robust (resp. non-robust) test for a path if the path is robust (resp.non-robust) testable and can also detect a subset of FS path delay faults.

We also address the reduction of over-testing. We propose a method to identify RTL paths which never propagate a value from the starting register to the ending register within one clock at normal operation. We refer to such path as Control-dependent Untestable Paths (CUPs).

Experimental results show that the proposed method can reduce hardware overhead without losing the quality of test.

2. Target circuit and fault

An RTL design generally consists of controller and data path, and they are connected each other by control signal lines and status signal lines. Our target part is the data path separated from the controller part. Note that we use information of control signals from the controller to identify CUPs. All control signals and status signals of the data path are assumed to be directly controllable and directly observable, respectively. A data path consists of hardware elements (e.g. PIs, POs, registers, multiplexers, operational modules, and observation modules) and lines to connect output ports of hardware elements with input ports of others. There are two types of input ports of a hardware element: data input ports and control input ports. Each data input port is reachable directly or indirectly from at least one PI. Each control input port is connected with control signal line. Similarly, there are two types of output ports of a hardware element: data output ports and status output ports. Each data output port is reachable directly or indirectly to at lease one PO. Each status output port is connected with status signal line. An operational module has one or two data input ports, one data output port and at most one status output port, and an observation module has one or two data input ports, one status output port, at most one control input port. We assume that (i) all lines have same bit width. (ii) There is no chaining of operational modules. Note that chaining modules can be regarded as *n* input and one output operational module. We relax the second assumption by extending the consideration of two input modules. We target all the path delay faults except for faults on paths which start at control inputs or end at status outputs.

3. SPC two pattern testability

3.1. SPC two-pattern test

In this section, a combinational block which consists of combinational hardware elements on input cone to a register is considered at RTL. We refer to an RTL path which is a target of testing as *on-path*. As opposed to on-path, we refer to an RTL path which supports to the propagation of a transition launching at the starting point of an on-path along an on-path as *off-path*. For the input port of an operational module on on-path, one of the RTL paths passing through the other port can be an off-path (See the left picture of Figure 1). In this paper, we assume that an operational module has one or two input ports and there is no chaining module, hence the number of off-paths is at most one for each on-path. An SPC two-pattern test is a pair of two consecutive vectors which launches transitions at the port corresponding to the starting point of the on-path and sets stable two consecutive vectors for the other ports of the combinational block. When SPC two-pattern tests are applied to a combinational block, the select signal of each MUX is fixed with an on-path or an off-path being selected. [6] showed that while the select signal of a MUX is fixed, propagation of the signals from the selected input to the output is independent of the signals at the other input. Therefore the on-path is testable if SPC two-pattern tests can be applied to starting point of the on-path and the off-path.

SPC two-pattern tests for combinational blocks can be generated by using a combinational test generation algorithm with constraints. To describe the constraints, we use the notation X and H. X denotes that it is possible to generate arbitrary vector and H means that the vector just before is held. In Figure 1, we show an example of constraints for ATPG. XX for an on-path (a bold line in the figure) denotes that it is possible to generate arbitrary two vectors consecutively. XH denotes that the first vector is an arbitrary vector and the second vector is the same as the first one. This is the input constraint for off-path. As we mentioned above, for the inputs other than those on on-path, off-path and the select signal line of each MUX, we do not care generated vectors, hence we denote merely XX.

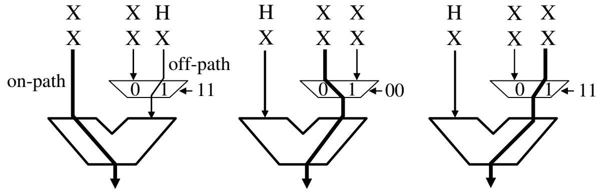

Figure 1. Constraints of ATPG to generate SPC two-pattern tests.

3.2. Quality of SPC two-pattern test

Smith[7] showed that a path delay fault is testable by a robust test if and only if there exits a robust single-input change (SIC) test for this fault, and Gharaybeh[8] showed that the same applies to non-robust tests. Their theorems show that there exist SIC robust tests for robust testable path delay faults and SIC non-robust tests for non-robust testable path delay faults. At gate level consideration, an SIC two-pattern test launches a transition for 1 bit of inputs of a combinational block, while an SPC two-pattern test can launch transitions for any bits of inputs of the corresponding port. Hence SPC two-pattern test can completely cover an SIC two-pattern test. In other words, there exists an SPC robust (resp. non robust) test for a robust (resp. non-robust) testable path delay fault without loss of test quality.

The remaining testable path delay faults are FS path delay faults. To test these faults, transitions are needed at multiple inputs. A FS path delay fault which needs transitions for some inputs of only on-path can be tested using an SPC two-pattern test. However the fault which needs transitions for some inputs of both on-path and off-path cannot be tested under the concept. By experiments, we examine that how many FS faults become untestable.

3.3. SPC two-pattern testability

We define SPC two-pattern testability for RTL paths. To test an RTL path which does not pass through an operational module with two input ports, one control path and one observation path are sufficient to test the RTL path. Control paths are the paths to justify test patterns from PIs to each register and observation paths are the paths to propagate the responses to POs. If we consider only one control path, we need not care about timing conflict to justify test patterns. Timing conflict means that more than or equal to two values are required to the same PI at the same time. Hence it is certainly possible to generate a control path by using a *thru* function[10], A thru function is added to an operational module in order to propagate a value along a control path or an observation path without changing the

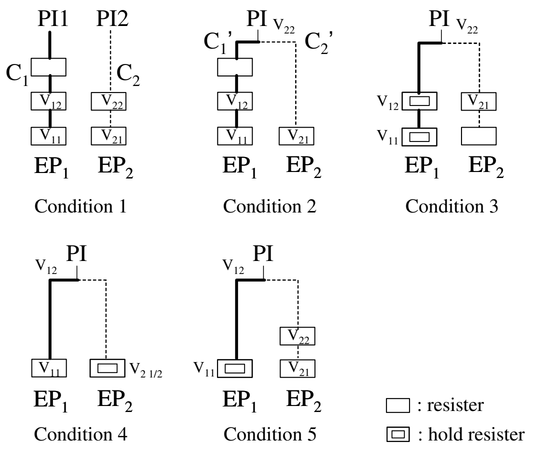

Figure 2. Conditions for C_1 and C_2.

value . The realization of a thru function is shown in Section 5. To test an RTL path $p \in P$ which passes through an operational module having two input ports, it is necessary to justify test patterns from a PI or PIs to appropriate registers by a pair of control paths C_1, C_2 and propagate test responses from an appropriate register to a PO by an observation path O_p, where C_1 is the path from a PI to the starting register of an on-path p, and C_2 is the path from a PI to the starting register of an off-path.

Definition 1: An RTL path p is SPC two-pattern testable if there exists a pair of control paths C_1 and C_2 that can apply SPC two-pattern tests to the combinational block and O_p that can observe the test responses.

3.3.1. Conditions for control paths

Here, to simplify the following discussion, we assume that there exists a thru function for each input port of every operational module in a data path. In the next section, we will propose an efficient DFT algorithm to add thru function to data paths. In order to support the application of SPC two-pattern tests with a pair of control paths C_1 and C_2, the difference between the sequential depths of C_1 and that of C_2 and/or the number of *hold* registers on C_1 and that of C_2 should be considered. The sequential depth of a control path C_i is the number of registers that appear on C_i and is denoted as $SD(C_i)$. Let EP_1 and EP_2 be the ending point of C_1 and that of C_2, respectively. If C_1 and C_2 are not disjoint, let C_1' and C_2' be the paths from the diverging point of C_1 and C_2 to EP_1 and EP_2, respectively. In the following theorem, we show necessary and sufficient conditions for a pair of control paths C_1 and C_2 to support SPC two-pattern tests.

Theorem 1: A pair of control paths C_1 and C_2 can justify SPC two-pattern tests to their ending points EP_1 and EP_2 if and only if C_1 and C_2 satisfy one of the following five conditions.

1. C_1 and C_2 are disjoint.
2. $|SD(C_1') - SD(C_2')| \geq 2$
3. There exist at least two hold registers on C_1'.
4. There exists at least one hold register on C_2'.
5. There exists at least one hold register on C_1' and $SD(C_2') - SD(C_1') = 1$

Examples of these conditions are shown in Figure 2.

Proof: An arbitrary SPC two-pattern test (V_1, V_2) is represented as $V_1 = v_{11} \& v_{21}$ and $V_2 = v_{12} \& v_{22}$. v_{11} and v_{12} are applied to an on-path. v_{21} and v_{22} are applied to an off-path and they are the same value.

Sufficiency: Since we assume that there exists a thru function between each input and the output of every operational module, we have only to consider timing conflicts. If C_1 and C_2 satisfy Condition 1, it is obviously possible to justify any SPC two-pattern test from PIs to EP_1 and EP_2 (see Condition 1 of Figure 2). With regard to Conditions 2,3,4 and 5, although C_1 and C_2 are not disjoint, it is also possible to justify any SPC two-pattern test without a timing conflict. In Condition 2, we first apply the first and the second partial vectors consecutively to the PI for the control path with higher sequential depth. Then we apply consecutively the remaining two vectors to the same PI. In Condition 3, we first load v_{11} and v_{12} into two hold registers on C_1' and hold the values, secondly we apply consecutively v_{21} and v_{22} to the PI. In Condition 4, we first load v_{21} into hold register on C_2' and hold the value. Then we apply v_{11} and v_{12} consecutively. In Condition 5, we first load v_{11} into hold register on C_1' and hold v_{11}, then we apply v_{21}, v_{22} and v_{12} consecutively.

Necessity: we assume that two control paths C_1 and C_2 do not satisfy any of the above five conditions. Such control paths satisfy all the following properties.

1. C_1 and C_2 are not disjoint.
2. $|SD(C_1') - SD(C_2')| < 2$
3. The number of hold registers on C_1' is at most one.
4. There is no hold register on C_2'.
5. There is no hold register on C_1' if $SD(C_2') - SD(C_1') = 1$.

All the possible pairs of control paths C_1 and C_2 that satisfy all the above properties are as follows.

- C_1 and C_2 are not disjoint and $|SD(C_1') - SD(C_2')| = 1$ and there is no hold register on both C_1' and C_2'.
- C_1 and C_2 are not disjoint and $|SD(C_1') - SD(C_2')| = 0$ and there is no hold register on both C_1' and C_2'.
- C_1 and C_2 are not disjoint and $SD(C_1') - SD(C_2') = 1$ and there is only one hold register on C_1'.
- C_1 and C_2 are not disjoint and $|SD(C_1') - SD(C_2')| = 0$ and there is only one hold register on C_1'.

Any pair of control paths C_1 and C_2 described above can not guarantee SPC two-pattern test. Therefore five conditions are the only conditions for a pair of control paths C_1 and C_2 to justify SPC two-pattern tests from a PI or PIs to EP_1 and EP_2. □

Here we consider relaxation of the assumption of the number of input ports of an operational module. The following theorem shows the sufficient conditions for an operational module with n input ports.

Theorem 2: n control paths support the application of SPC two-pattern tests for an RTL path p if either of the following conditions is satisfied.

1. Any pair of n control paths are disjoint.
2. With regard to each pair of control paths for off-paths which are not disjoint, the mutually disjoint parts from the diverging point to both ending points cross at least one hold register.

The proof of this theorem is similar to that of Theorem 1.

As we mentioned in this subsection, to guarantee SPC two-pattern test, a register with hold function is needed even if the difference between sequential depths of C_1 and that of C_2 is zero. However to guarantee arbitrary two-pattern test in such case, we need more complex hardware element for DFT.

3.3.2. Conditions for observation paths

To observe a test response, the value captured at the ending register of an RTL path have to be propagated to a PO without changing the value. Fortunately, we need not care about timing conflict because only one observation path is sufficient to propagate the value. Hence to guarantee the propagation, it is sufficient to add a thru function to each operational module on the observation path.

4. The conditions to identify CUPs

We can obtain information about state transitions of the controller and control signals from the controller to the data path at each state by analyzing the RTL description of the circuit. By considering the timing of data transfer between registers and the structure of a data path, we idetify RTL paths as Control-dependent Untestable paths (CUPs).

Let P be a set of RTL paths in a data path and now we consider whether $p \in P$ is CUP or not. Let R_s be the register which is the starting point of p, and let R_e be the register which is the ending point of p. Let C_{Rs} and C_{Re} be load enable signals of registers R_s and R_e, respectively. If the load enable signal of a register is equal to '1', the register loads a value, otherwise, holds its value. Note that in case the register does not have *hold* function, we assume that a load enable signal line is connected to the register, and the value of that signal is always '1'. In case the starting point of p is a PI or the ending point of p is a PO, the PI or the PO is treated as a register with no *hold* function. Let M_i and C_{M_i} $(1 \leq i \leq n)$ be a MUX on p and its select signal, respectively. When M_i selects the input on p, the value of the select signal is denoted as $C_{M_i} = p_{M_i}$. Let S_i and S_j be states of the controller. S_i and S_j is said to be consecutive if there exists a direct transition from S_i to S_j. Let $C_{M_n} = (a_i, a_j)$ be a select signal pair of consecutive two states.

Definition 2: An RTL path p is control-dependent untestable path (CUP) if either of following two conditions is satisfied for any consecutive two states.

1. $C_{Rs} = (0, -) \vee C_{Re} = (-, 0)$ $\quad -$: don't care
2. $\vee_{i=1}^{n} \{C_{M_i} \neq (-, p_{M_i})\}$

Theorem 3: All the gate-level paths corresponding to an RTL path p are non-robust untestable if p is CUP.

proof: For the first condition of Definition 2, R_s does not launch a transition at S_i, or R_e does not capture the response at S_j. For the second condition, p is not selected at S_j and this prevents propagation of transitions from R_s to R_e. Therefore, p is non-robust untestable. □

5. DFT method for RTL data path

In this section, we propose a DFT method which makes RTL paths except for CUPs in data paths SPC two-pattern testable.

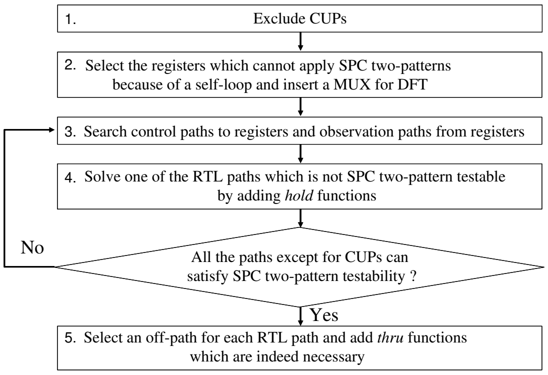

Figure 3. The flow of our DFT algorithm.

5.1. DFT element

Additional hardware elements of DFT are multiplexer (MUX), hold function and thru function. We use a MUX to make a new RTL path from a PI to a register. A hold function is added to a register for the purpose of holding the value according to need, and it is realized by adding a MUX just before the register to feedback a value from the output to the input. A thru function is explained briefly in Section 4. For a common module, such as adder or multiplier, it is realized by providing a constant value to the other input. It can be provided by adding a mask element. A mask element generates a constant depending on its control signal. For a more complex module or a module with one input port, we cannot realize the thru function by only providing a constant, then we deal with the thru function by bypassing the module using a MUX.

5.2. Algorithm for adding DFT elements

Figure. 3 shows the flow of the proposed DFT algorithm.

Step 1: We extract CUPs according to conditions of Theorem 3, and remove them from the consideration for test. Accordingly, not only over-testing is relaxed but it may also be possible to reduce hardware overhead if an RTL path which cannot apply SPC two-pattern tests without DFT is judged as CUP.

Step 2: There are some RTL paths which start at a register and go back to the same register. There are many cases where SPC two-pattern tests cannot be applied to such an RTL path because it is structurally difficult to satisfy the conditions of Theorem 1. Since it is only possible to make such an RTL path SPC two-pattern testable by adding MUX (hold function cannot solve this problem) and making a new control path from a PI, we first solve the place. To find RTL paths forming a loop we consider a circuit as a graph consisting of four types of node, R, Op, Fo and M, and directed edges. These nodes R, Op, Fo and M correspond to a register, an operational module, a fanout branch and a MUX, respectively, and they are connected by directed edges corresponding to the signal lines of the circuit. We refer to the loop which starts at R_i node and go back to the same node without passing through any other R_j node as self-loop.

It is impossible to apply SPC two-pattern tests to the RTL path corresponding to the self-loop if there is no M_k node whose input can reach a PI not passing through the self-loop between Op_n node and R_i node. If one of the RTL paths which starts at R_i node and passes through Op_n node is not CUP, the RTL path should be modified into SPC two-pattern testable. Such an RTL path can be solved by inserting a MUX between Op_n and R_i, and adding a new path from a PI to the MUX. Here we consider the self-loop $R1$-$m1$-$m2$-$Add1$-$m5$-$R1$ in figure 4 as an example, and each node is named R_1, M_1, M_2, Op_1 and M_5, respectively. There is no M_k node between Op_1 and R_1 which can reach PI not passing through the self-loop. If one of the RTL paths starting at $R1$ is not CUP, a MUX is added to the place between Op_1 and R_1 then a new RTL path $PI2$-MUX-$R1$ is made. When there are some PIs in a circuit, we select the PI such that the pair of control paths is disjoint to satisfy condition 1 of Theorem 1. However if there is only one PI in the circuit, we make a new RTL path from the PI. In this case, if the pair of control paths may not satisfy any conditions from second to fifth, hold function is added in Step 4.

Step 3: This step selects candidates for control and observation paths to each register by heuristics. The decision of control and observation paths is step 4.

In order to reduce area overhead and test application time, control paths is selected as they form trees whose source nodes are PIs, accordingly each register is reachable from a PI via a control path with the minimum sequential depth. To search such control paths, we represent the data path as a port graph $G = (V, E)$[10]. V is the set of all input ports and output ports of modules, and E is the set of all directed edges corresponding to the signal lines in the data path and relation between an input and an output of each module (we call the latter edge inside edge). We apply *breadth first search* (BFS) with respect to the number of registers to the port graph. From the result of the search, we obtain trees which contain the information of control paths with the minimum sequential depth from PIs to registers. The search ends when all the registers become reachable. In [6][10], to search control paths they also make use of BFS. In this paper, we add a new condition for search which takes advantage of the feature of SPC two-pattern testability. Considering the conditions of Theorem 1, it is desirable that there exists a register with hold on a control path. Therefore we choose a path starting at a hold register if there are some paths which can be chosen at the same sequential depth.

Next we search observation paths with the minimum depth. The search from each register to a PO make use of observation trees. Observation trees are made by performing the BFS from each PO on the port graph which is generated by reversing the direction of edges, then we take precedence over the path with control tree if there are some choices, for example, from the output port of an operational module to each input port, to share thru function between control paths and observation paths.

Step 4: For one of the RTL paths which is not SPC two-pattern testable, we modify it into SPC two-pattern testable path by adding a hold function to its starting register. In this step, RTL paths which are not CUPs i.e. the RTL paths need to be tested, and whose pairs of control paths have not yet been determined is dealt with. We first judge RTL paths one by one whether it satisfies the condition of Theorem 1 or not. If the RTL path is SPC two-pattern testable,

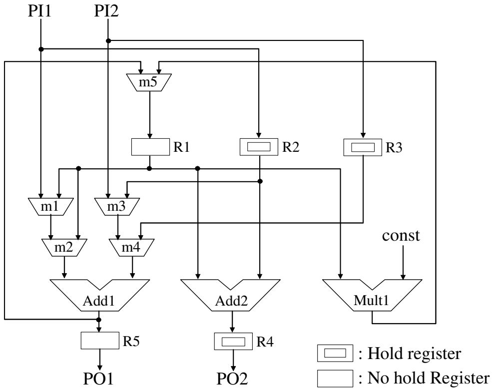

Figure 4. LWF benchmark circuit

the pair of control paths generated in Step 3 is determined. However, if the RTL path has no pair of control paths satisfying any one of the five conditions at all, it is sufficient to add a hold function to one of the registers which can be the starting points of off-paths in order to satisfy condition 4 of Theorem 1. Among the registers, a hold function is added to the register with the smallest sequential depth. Consequently, more control paths share the hold function because a set of control paths forms trees. Here we consider testing of RTL path $R2$-$Add2$-$R4$ in figure 4. The control paths to $R2$ and $R1$ are $PI1$-$R2$ and $PI2$-Additional MUX-$R1$. The additional MUX was already added between $m5$ and $R1$ in Step 2. Since the pair of control paths cannot satisfy any conditions of Theorem 1, an hold function is added to $R1$. If a hold function is added, go back to Step 3 and make the control trees again for the modified circuit. Then only unsolved RTL paths will be target of Step 4 again.

Step 5: We consider how to realize shorter test application time when there are some choices of off-paths for testing an on-path. We first try to select an off-path having a control path with the minimum sequential depth among them and disjointed from that of on-path. If there does not exist such an off-path, that of the minimum depth is selected. We assumed that thru functions are available for all the input ports of all operational modules, however some of them may not be necessary. It is indeed necessary to add a thru function between an input port and an output port, corresponding to inside edges on control or observation paths, of an operational module. To realize a thru function, we first search a support path considering timing conflict. A support path is a path from a PI to an input of an operational module, which can justify a constant. If there does not exist such a path, we add a mask element or a MUX for bypass to realize it.

6. Experimental Results

In this section, we evaluate the effectiveness of the proposed DFT method compared to the previous DFT method for HTPT[6] with regard to area overhead and test application time. The DFT method which guarantees HTPT data path has similar advantages to enhanced-scan approach and can reduce the area overhead and the test application time. The circuit characteristics of RTL benchmarks used in the experiments are shown in Table 1. Paulin, LWF are widely used circuits. RISC and MPEG are more practi-

Table 1. Circuit characteristics.

Circuit	BW	#PIs	# POs	# REGs	# RTL path	Area
Paulin	16	2	2	7	29	10,550
LWF	16	2	2	5	19	3,322
RISC	32	1	3	40	10,108	94,302
MPEG	8	7	16	241	651	77,554

Table 2. Results of DFT and test generation.

		Area overhead[%]		Test application time[cyc]		# CUPs
Circuit	BW	Proposed	HTPT	Proposed	HTPT	Proposed
Paulin	8	5.13	11.56	785,136	1,645,335	11
	16	3.30	7.43	-	-	11
LWF	8	7.43	15.25	38,913	74,792	3
	16	6.38	13.99	1,638,660	3,162,124	3
RISC	32	0.64	1.99	$3T_{ALU}$+2	$4T_{ALU}+2$	512
MPEG	8	4.64	9.35	$186T_M$+2079	$186T_M$+2016	0

cal and larger circuits designed by industry. In this experiments, we used the logic synthesis tool Design Compiler (Synopsys). To generate SPC two-pattern tests, we used the combinational test generation algorithm which supports constraints[11].

Our proposed method guarantee to detect all the faults in a circut which are detectable in combinational logic blocks separated from the circuit. With regard to robust and non-robust path delay faults the fault coverage of our method is equal to that for HTPT data path if CUPs are not considered. Table 2 shows the results of area overhead, test application time and the number of CUPs. For all benchmark circuits, area overhead of the proposed DFT method is lower than that of HTPT data path. From the results of Paulin and LWF, the larger the size of circuit, the smaller the area overhead. The difference between area overhead of the proposed method and that of the previous one become large if there are many registers which are reached from the same PI and at the same sequential depth. For 8 bit Paulin, 8bit LWF and 16 bit LWF, the proposed method can reduce test application time to about 50% of that for HTPT. The main reason is that the number of target faults can be reduced by removing CUPs. For Paulin and LWF, we judged eleven and three RTL paths as CUPs, respectively. The other reason is that previous method adds extra register to these circuits. In such case, extra one cycle is necessary for loading data into such a register. For 16 bit Paulin, RISC and MPEG, it is not practical to test all paths in the data path because the number of paths is extremely large. Therefore we consider the critical parts which affect the difference between test application time of the proposed method and that of previous one. For 16 bit Paulin, a combinational block composed of two multipliers is the critical part. In the proposed method, many RTL paths through the block are identified as CUPs. However, we cannot estimate the difference between the number of test patterns for the block in the proposed method and that in the previous method. Hence, we cannot perform symbolic analysis. For RISC, an ALU is critical part and its number of tests is denoted as T_{ALU} in the table. The proposed method can reduce 25% compared to the previous one. For MPEG, a sub circuit composed of 64 identical structures of a chaining module is critical. The number of tests is denoted as T_M in the table. For both methods, the test application times are almost same. For all circuit except for MPEG, since CUPs are identified, over-testing problem is alleviated.

In subsection 3.2, we showed that SPC two-pattern tests can test a subset of FS path delay faults. Here, we show that the number of FS path delay faults in three simple operational modules which can be tested by SPC two-pattern tests. For a 32 bit adder, there are 1638 FS path delay faults and all the faults can be tested by SPC two-pattern tests. For a 32 bit subtracter, 1042 of the total 1054 FS path delay faults are tested. For a 8 bit multiplier, 947 of the total 49328 FS path delay faults are tested. From these results, SPC two-pattern tests do not always test all the FS path delay faults of an operational module. If it is necessary to test FS path delay faults of such operational module which is SPC two-pattern test resistant, we can guarantee application of arbitrary two-pattern tests by applying our previous DFT method only for the module.

7. Conclusion

This paper proposed a concept of Single-Port-Change (SPC) two-pattern testability and presented an efficient non-scan DFT method for data path. The proposed method can reduce area overhead and test application time compared to the previous DFT method for hierarchical two-pattern testability without losing the quality of test. Moreover, we alleviated over-testing by removing the control-dependent untestable paths from the consideration of test.

Acknowledgements The authors would like to thank Dr. Tomokaze Yoneda and Mr. Virendra Singh (Nara Institute of Science and Technology) for their valuable discussion and their cooperation on this experiment. This work was supported in part by 21st Century COE Program and in part by Japan Society for the Promotion of Science (JSPS) under Grants-in-Aid for Scientific Research B(2)(No. 15300018) and for Young Scientists (B) (No.17700062).

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